## PowerPhase, Dual N-Channel SO8FL 30 V, High Side 25 A / Low Side 49 A

#### Features

- Co-Packaged Power Stage Solution to Minimize Board Space
- Minimized Parasitic Inductances
- Optimized Devices to Reduce Power Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### Applications

- DC–DC Converters
- System Voltage Rails
- Point of Load

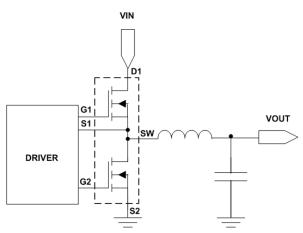
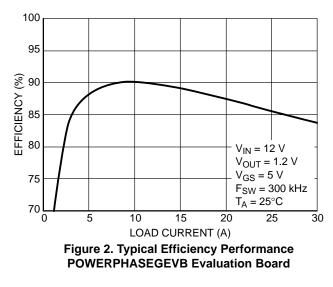


Figure 1. Typical Application Circuit

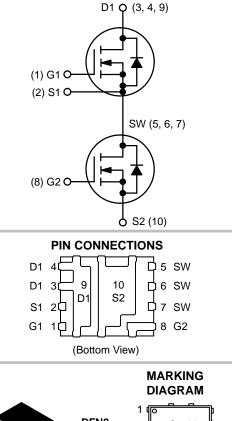


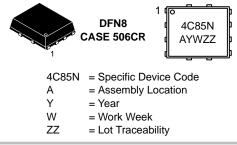


## **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
Q1 Top FET	3.0 mΩ @ 10 V	05 A
30 V	4.3 mΩ @ 4.5 V	25 A
Q2 Bottom FET	0.8 mΩ @ 10 V	40.4
30 V	1.2 mΩ @ 4.5 V	49 A





#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 10 of this data sheet.

#### Table 1. MAXIMUM RATINGS (TJ=25°C unless otherwise stated)

Paramet	Symbol	Value	Units			
Drain-to-Source Voltage			Q1	V <sub>DSS</sub>	30	V
			Q2			
Gate-to-Source Voltage			Q1	V <sub>GS</sub>	±20	V
			Q2	-		
Continuous Drain Current $R_{\theta JA}$ (Note 1)		$T_A = 25^{\circ}C$	Q1	I <sub>D</sub>	20.1	А
		$T_A = 85^{\circ}C$			14.5	
		$T_A = 25^{\circ}C$	Q2		39	
		$T_A = 85^{\circ}C$			28.1	
Power Dissipation		<b>T</b> 0500	Q1	PD	1.95	W
R <sub>0JA</sub> (Note 1)		$T_A = 25^{\circ}C$	Q2			
Continuous Drain Current $R_{\theta JA} \le 10$ s (Note 1)		$T_A = 25^{\circ}C$	Q1	I <sub>D</sub>	25.4	А
		$T_A = 85^{\circ}C$			18.3	
	Steady State	$T_A = 25^{\circ}C$	Q2		49.2	
		$T_A = 85^{\circ}C$			35.5	
Power Dissipation R <sub>θJA</sub> ≤ 10 s (Note 1)		T 0500	Q1	PD	3.10	W
		T <sub>A</sub> = 25°C	Q2			
Continuous Drain Current		$T_A = 25^{\circ}C$	Q1	Ι <sub>D</sub>	15.4	А
R <sub>θJA</sub> (Note 2)		$T_A = 85^{\circ}C$			11.1	
		$T_A = 25^{\circ}C$	Q2		29.7	
		$T_A = 85^{\circ}C$			21.4	
Power Dissipation		T 25°C	Q1	PD	1.13	W
R <sub>0JA</sub> (Note 2)		$T_A = 25^{\circ}C$	Q2			
Pulsed Drain Current		T <sub>A</sub> = 25°C	Q1	I <sub>DM</sub>	300	А
		tp = 10 μs	Q2		525	
Operating Junction and Storage Temperature			Q1	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
			Q2			
Source Current (Body Diode)			Q1	۱ <sub>S</sub>	10	А
			Q2		10	
Drain to Source DV/DT				dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy (	T <sub>J</sub> = 25°C,	$I_L = 19 A_{pk}$	Q1	EAS	34.5	mJ
$V_{DD} = 50 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ L} = 0.1 \text{ mH}, \text{ R}_{G} = 25 \Omega$		$I_L = 26 A_{pk}$	Q2	EAS	222	
Lead Temperature for Soldering Purposes (1/8" fro	m case for 10 s	;)		ΤL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
Surface-mounted on FR4 board using the minimum recommended pad size of 100 mm<sup>2</sup>.

#### Table 2. THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Units
Junction-to-Ambient - Steady State (Note 3)	R <sub>θJA</sub>	64.2	°C/W
Junction-to-Ambient - Steady State (Note 4)		110.5	
Junction–to–Ambient – (t $\leq$ 10 s) (Note 3)		40.3	

Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu
Surface-mounted on FR4 board using the minimum recommended pad size of 100 mm<sup>2</sup>

## Table 3. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	FET	Test Condition		Min	Тур	Max	Units
OFF CHARACTERISTICS	OFF CHARACTERISTICS							
Drain-to-Source Breakdown	V <sub>(BR)DSS</sub>	Q1		250 4	30			V
Voltage		Q2	$V_{GS} = 0 V, I$	ID = 250 μA	30			
Drain-to-Source Breakdown	$V_{(BR)DSS}$ / $T_J$	Q1				19		mV/°C
Voltage Temperature Coefficient		Q2				17		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	Q1		$T_J = 25^{\circ}C$			1	μΑ
			V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	$T_J = 125^{\circ}C$			10	
		Q2	20	$T_J = 25^{\circ}C$			1	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	Q1	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
		Q2	V <sub>GS</sub> =	= 20 V			100	

#### **ON CHARACTERISTICS** (Note 5)

Gate Threshold Voltage	V <sub>GS(TH)</sub>	Q1	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA		1.3		2.1	V
		Q2	$v_{GS} = v_{DS},$	I <sub>D</sub> = 250 μA	1.3		2.1	
Negative Threshold Temperature	$V_{GS(TH)}$ / $T_J$	Q1				4.3		mV/°C
Coefficient		Q2				4.6		
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	Q1	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		2.2	3.0	mΩ
			$V_{GS}$ = 4.5 V	I <sub>D</sub> = 20 A		3.3	4.3	
		Q2	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		0.6	0.8	
			$V_{GS}$ = 4.5 V	I <sub>D</sub> = 30 A		0.95	1.2	

#### CAPACITANCES

Input Capacitance	C <sub>ISS</sub>	Q1		1960	pF
		Q2		6660	
Output Capacitance	C <sub>OSS</sub>	Q1		1230	
		Q2	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V	3660	
Reverse Capacitance	C <sub>RSS</sub>	Q1		102	
		Q2		126	

#### **CHARGES & GATE RESISTANCE**

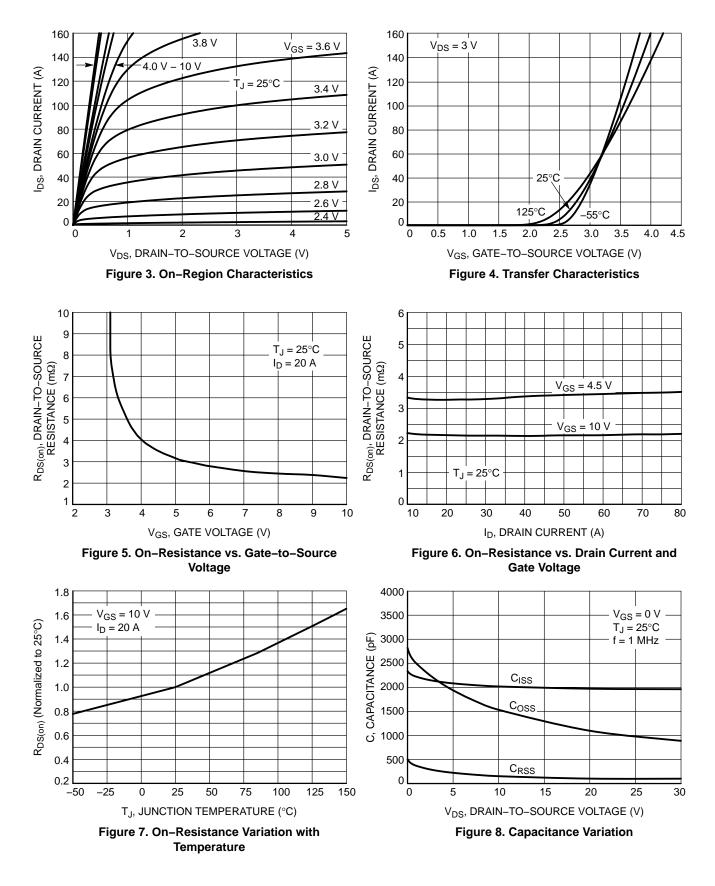
Total Gate Charge	Q <sub>G(TOT)</sub>	Q1		15	nC
		Q2		45.2	
Threshold Gate Charge	Q <sub>G(TH)</sub>	Q1		1.5	
		Q2	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 20 A	4.5	
Gate-to-Source Charge	Q <sub>GS</sub>	Q1		5.0	
		Q2		15	
Gate-to-Drain Charge	Q <sub>GD</sub>	Q1		5.2	
		Q2		11.8	
Total Gate Charge	Q <sub>G(TOT)</sub>	Q1		32	nC
		Q2	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 20 A	99.3	
Gate Resistance	R <sub>G</sub>	Q1	T 25°C	1.0	Ω
		Q2	$T_A = 25^{\circ}C$	1.0	

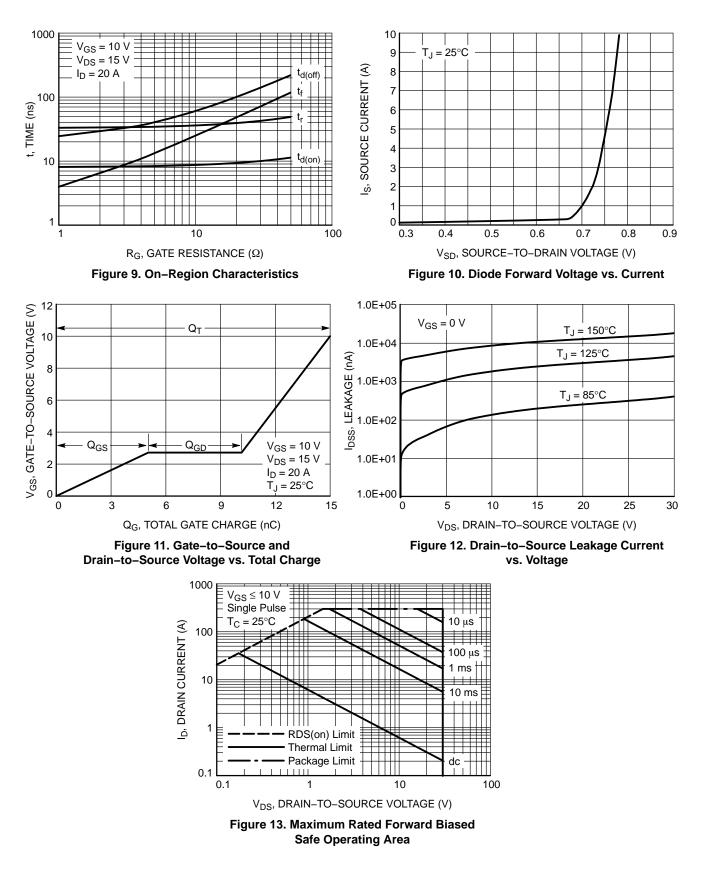
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2% 6. Switching characteristics are independent of operating junction temperatures

## Table 3. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	FET	Test Co	ndition	Min	Тур	Max	Units
SWITCHING CHARACTERISTI	CS (Note 6)					-	•	-
Turn–On Delay Time	t <sub>d(ON)</sub>	Q1				10.3		ns
	. ,	Q2				19.5		
Rise Time	t <sub>r</sub>	Q1				37		
		Q2	V <sub>GS</sub> = 4.5 V.	Vps = 15 V.		27		
Turn–Off Delay Time	t <sub>d(OFF)</sub>	Q1	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 20 A, F	$R_{G} = 3.0 \Omega$		20		
	. ,	Q2				47		
Fall Time	t <sub>f</sub>	Q1				5.6		
		Q2				15		
SWITCHING CHARACTERISTI	<b>CS</b> (Note 6)							
Turn–On Delay Time	t <sub>d(ON)</sub>	Q1	Voo = 10 V Voo = 15 V			8.0		ns
	. ,	Q2				12.6		
Rise Time	tr	Q1				31.5		
		Q2				22.7		
Turn–Off Delay Time	$\begin{array}{c c} & Q2 & \\ \hline \\ ay \ Time & t_{d(OFF)} & Q1 & \\ \end{array}  \begin{array}{c} V_{GS} = 10 \ V, \ V_{DS} = 15 \ V, \\ I_D = 20 \ A, \ R_G = 3.0 \ \Omega & \\ \end{array}$			25				
	Q2		60					
Fall Time	t <sub>f</sub>	Q1				4.0		
		Q2				12.2		
DRAIN-SOURCE DIODE CHAF	RACTERISTICS							
Forward Voltage	V <sub>SD</sub>	Q1	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.78		V
			$I_{\rm S} = 10$ A	T <sub>J</sub> = 125°C		0.62		
		Q2	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.75		1
			$I_{\rm S} = 10  {\rm A}$	T <sub>J</sub> = 125°C		0.55		
DRAIN-SOURCE DIODE CHAF	RACTERISTICS							
Reverse Recovery Time	<sup>t</sup> RR	Q1				40		ns
		Q2				73		
Charge Time	ta	Q1				20		
-		Q2	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 2 A			40		
Discharge Time	tb	Q1				20		
ŭ		Q2				33		
Reverse Recovery Charge	Q <sub>RR</sub>	Q1				37		nC
	-1/1/	Q2				137		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width  $\leq 300 \ \mu$ s, duty cycle  $\leq 2\%$ 6. Switching characteristics are independent of operating junction temperatures





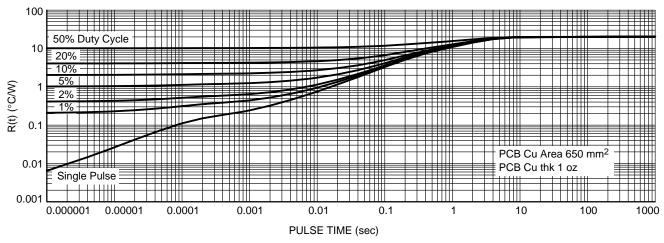
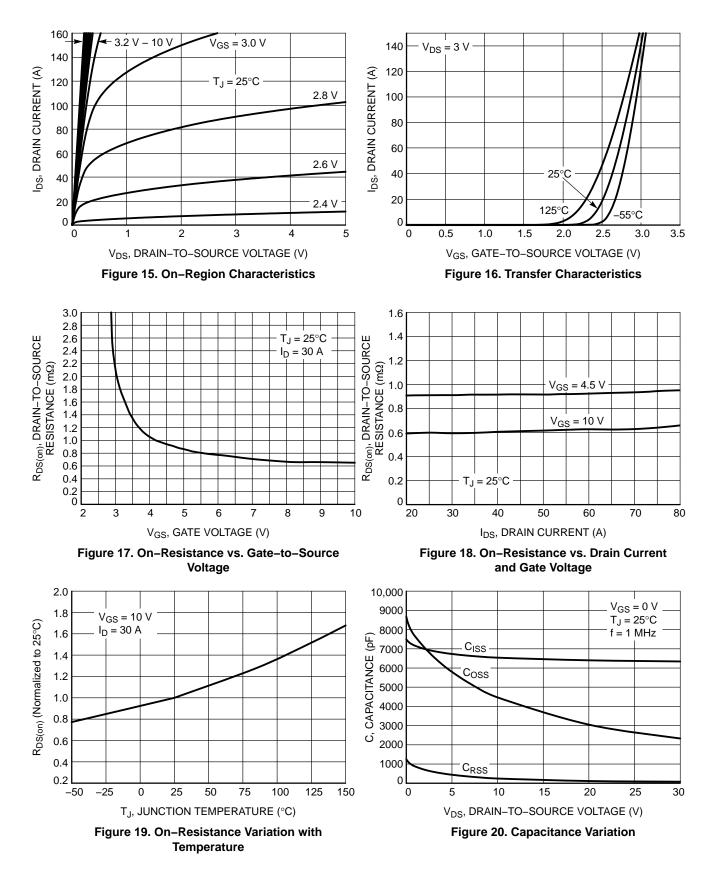
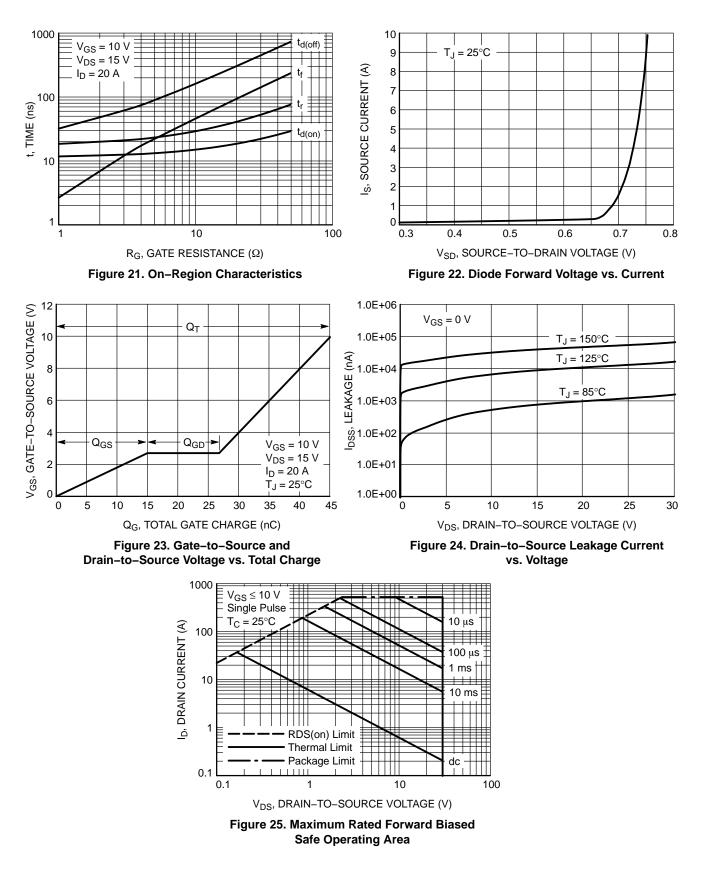


Figure 14. Thermal Characteristics





## **TYPICAL CHARACTERISTICS – Q2**

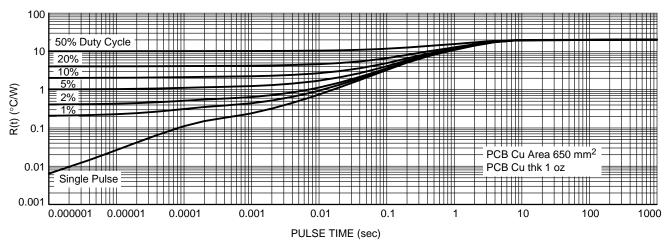


Figure 26. Thermal Characteristics

#### **Ordering Information**

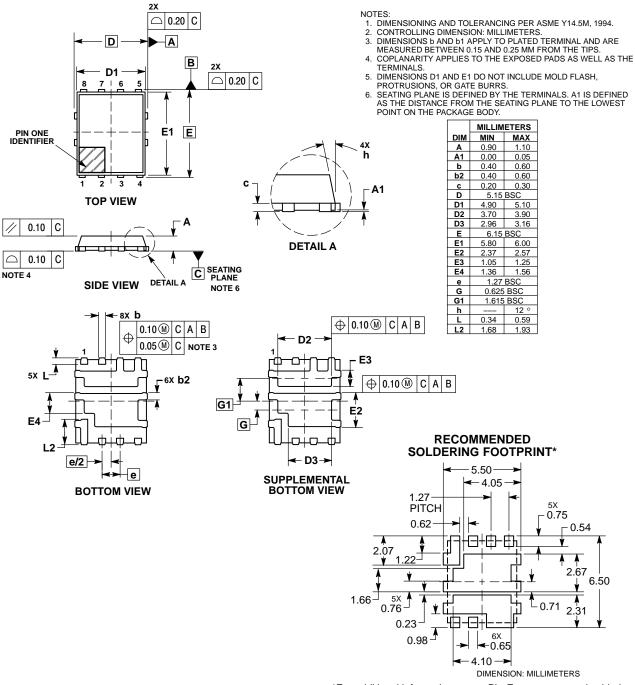
Device	Package	Shipping <sup>†</sup>
NTMFD4C85NT1G	DFN8 (Pb–Free)	1500 / Tape & Reel
NTMFD4C85NT3G	DFN8 (Pb–Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

#### DFN8 5x6, 1.27P PowerPhase FET

CASE 506CR ISSUE B



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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